

AK2570

Feed Forward APC LSI for LD Module

DESCRIPTION

AK2570 is the monolithic CMOS LSI has the function of 'Feed Forward Automatic Power Control (APC)' for the Laser Diode (LD) module and maintains the emission intensity of the LD module constant with the high accuracy.

For stabilizing the emission intensity of the LD module affected by the ambient temperature, AK2570 feeds the compensation voltage from the 2channels - 8bits D to A converter to control the Bias- and the Modulation- current for the LD module. The compensation voltage corresponds to the temperature characteristic data of the LD module retained in the on-chip EEPROM and the ambient temperature detected by the on-chip thermo-sensor.

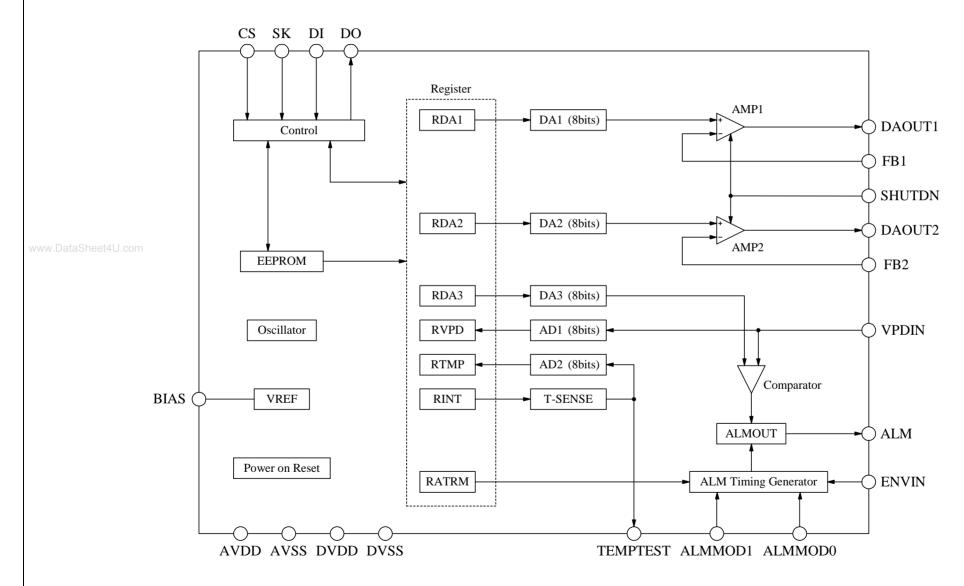
AK2570 outputs the alarm signal for the weakened LD emission caused by the aging degradation with comparing the alarm threshold level and the signal from the monitoring Photo Diode (PD).

The data of the compensation voltage and the alarm threshold level retained in the on-chip EEPROM can be set to suit for the characteristics of each LD module.

FEATURE

- Realizing all APC function on 1 silicon chip
- Controlling the driving current (the Bias- and the Modulation- current) for the LD module
 - * Consisting of the 2channels 8bits D to A converter and the Op-amp
- EEPROM (Electrically Erasable Programmable Read Only Memory)
 - * The Non-volatile Memory
 - * The memory capacity: Address 9bits × Data 16bits
 - * Retaining the data of the compensation voltage and the trimming data of the T-SENSE offset voltage and the ALM timing for each LD module.
- On-chip Thermo-sensor (T-SENSE)
 - * Detecting the ambient temperature and converting the detected temperature to the voltage
- On-chip Alarm circuit
 - * Outputting the alarm signal for the weakened LD emission caused by the aging degradation
- On-chip Oscillator
- On-chip Power on reset circuit
- Serial interface
- +3.3V±10% single voltage supply
- Low power consumption (30mA [max])
- Small package (20pin SSOP : 7.9mm ×7.4mm)

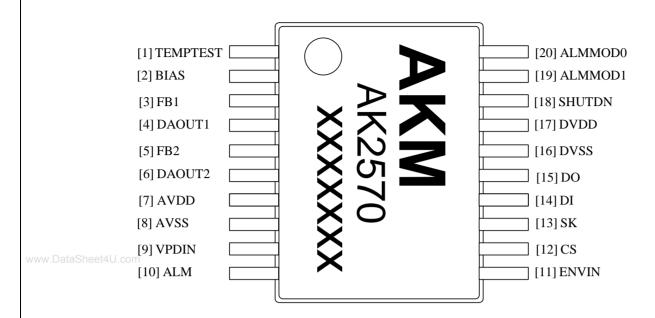
BLOCK DIAGRAM



AK2570 consists of these circuit blocks as below.

Circuit block	Functional description
Oscillator	This circuit generates the standard clock that settles the timing for the sequence of the
Oscillator	internal circuit in "Self-operation mode (Ordinary mode)".
VREF	This circuit generates the reference voltage for the A to D converter, the D to A converter
VKEF	and the T-SENSE.
	This circuit is the thermo-sensor, outputs the voltage corresponding to the ambient
T-SENSE	temperature, i.e. the temperature to voltage converter, and transfers this output voltage to
	AD2. Also it integrates the offset adjustment circuit that cancels the distribution.
	The A to D converter encodes the input voltage at VPDIN-pin (the signal from the
AD1	monitor PD) to the 8bits digital data. It is possible to read the encoded data of monitor PD
ADI	signal (the reference data for RDA3) held in RVPD register and to set the alarm threshold
ataSheet4U.com	level for the degraded LD in "Training mode".
	The A to D converter encodes the T-SENSE output signal to the 8bits digital data. In
	"Self- operation mode", the encoded data of the ambient temperature detected by the
AD2	T-SENSE is converted to the EEPROM address and utilized for reading the temperature
	characteristic data of the LD retained in the EEPROM. In "Training mode", it is possible
	to read the encoded data of the detected temperature held in RTMP register.
	This block consists of the D to A converter and the Op-amp and controls the Bias- or the
DA1,	Modulation- current for the LD. DA1 decodes the 8bits digital data held in RDA1 register
AMP1	to the compensation voltage for the temperature drift of the LD. Inputting the 'H' level
	signal to SHUTDN-pin makes that DAOUT1-pin outputs '0V (min.)'.
	This block consists of the D to A converter and the Op-amp and controls the Bias- or the
DA2,	Modulation- current for the LD. DA2 decodes the 8bits digital data held in RDA2 register
AMP2	to the compensation voltage for the temperature drift of the LD. Inputting the 'H' level
	signal to SHUTDN-pin makes that DAOUT2-pin outputs '0V (min.)'.
DA3, ALMOUT,	This block outputs the 'H' level alarm signal from ALM-pin in the case that the
Comparator, ALM	monitoring PD signal becomes lower than the alarm threshold level retained in the
Timing Generator	EEPROM and held in RDA3 register, and this case is caused by the aging degradation.
	This memory is the non-volatile memory, has the capacity 'Address 9bits × Data 16bits'
	and retains the data as below,
EEPROM	1. The temperature compensation data for the LD (transferred to RDA1 and RDA2 registers)
LEI KOWI	and the alarm threshold level data for the degraded LD (transferred to RDA3 register)
	corresponding to the ambient temperature (the output from the T-SNESE and AD2).
	2. The trimming data for the T-SENSE offset and the ALMOUT timing.
	This circuit temporarily stores the ambient temperature data (in RTMP register), the
Register	temperature compensation data for the LD (in RDA1 and RDA2 registers), the alarm
	threshold level data (in RDA3 register) and so on.
Control	This circuit controls the internal circuit, e.g. registers, with the serial interface.
Power on Reset	At 'Power ON', this circuit initializes the data in all registers (see p.9) and sets AK2570 in
1 Owel on Reset	"Self-operation mode".

PIN ASSIGNMENT



No	Name	I/O	Type	Function	AC load	DC load	Remark
1	TEMPTEST	О	Analog	Output the voltage generated by the T-SENSE (Factory use)			
2	BIAS	О	Analog	Output the current reference determined by the external resistance			[Note 1]
3	FB1	I	Analog	Input the feed back voltage to AMP1 for the gain control			
4	DAOUT1	О	Analog	Output the compensation voltage [1] for the LD	< 20pF		
5	FB2	I	Analog	Input the feed back voltage to AMP2 for the gain control			
6	DAOUT2	О	Analog	Output the compensation voltage [2] for the LD	< 20pF		
7	AVDD	I	Power	Supply the power for the analog part (+3.3V)			
8	AVSS	I	Power	Ground the analog part (0V)			
9	VPDIN	I	Analog	Input the signal of the monitor PD			
10	ALM	О	CMOS	Output the aging alarm	< 20pF		
11	ENVIN	I	CMOS	Input the envelope signal used at burst transmission			
12	CS	I	CMOS	Input the Chip Select signal with the serial interface			[Note 2]
13	SK	I	CMOS	Input the Shift clock with the serial interface			
14	DI	I	CMOS	Input the Data with the serial interface			
15	DO	О	CMOS	Output the Data with the serial interface	< 100pF		
16	DVSS	DVSS I Power Ground the digital part (0V)					
17	DVDD I Power Supply the power for the digital part (+3.3V)						
18	SHUTDN I CMOS Input the shut down signal for DA1 and DA2		Input the shut down signal for DA1 and DA2			See P.15	
19	ALMMOD1	I	CMOS	Input the select signal [1] for the aging alarm mode			See P.15
20	ALMMOD0	I	CMOS	Input the select signal [0] for the aging alarm mode			See P.15

[Note 1] : Kindly insert the external register 75k Ω (±1%) between BIAS-pin and AVSS.

[Note 2]: It is necessary to input the 'L' level signal to CS-pin at 'Power ON'.

FUNCTIONAL DESCRIPTION

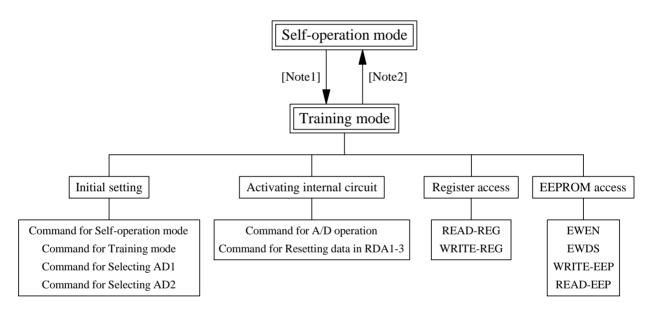
1. Explanation for the 'mode'

AK2570 has the 2 operational modes, "Self-operation mode" and "Training mode".

After executing the evaluation and the adjustment for the LD module including AK2570 in "Training mode", it is possible to use AK2570 ordinarily in "Self-operation mode" for compensating the temperature drift of the LD module.

"Self-operation mode" is the ordinary operational mode. If the ambient temperature drifts, AK2570 can maintain the emission intensity of the LD module constant by executing the APC operation, i.e. controlling the Bias- and the Modulation- current for the LD module, periodically (the compensation period is about 100msec) in "Self-operation mode". (See p.6) On the other hand, in "Training Mode", it is possible to evaluate and adjust AK2570 and the LD module by the access to the data in the EEPROM and the registers. (See p.7)

[a] Constitution of the mode and the command



- [Note 1] While operating in "Self-operation mode", it is possible to shift to "Training mode" by executing 'Command for Training mode' and this is the only available command. That is to say that any other command is not effective in "Self-operation mode".
- [Note 2] On the other hand, while operating in "Training mode", it is possible to shift to "Self-operation mode" by executing 'Command for Self-operation mode' or forcing the 'L' level signal to SK-pin for 50ms more and AK2570 shifts to "Self-operation mode" with behaving as same as the operation at 'Power ON'.

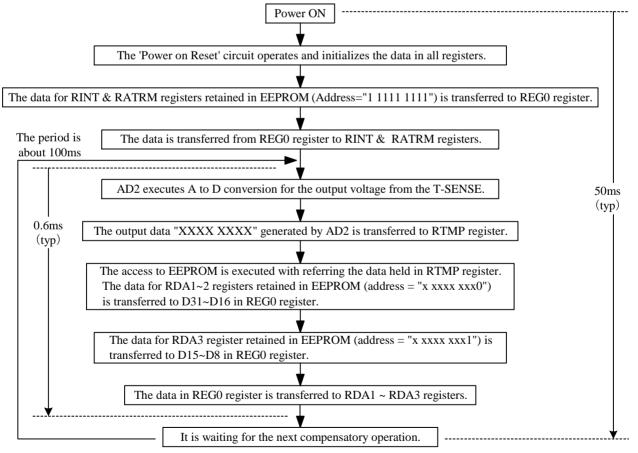
[b] Explanation for the modes and the commands

(1) Self-operation mode

The on-chip 'Power on Reset' circuit initializes the data in all registers and sets AK2570 in "Self-operation mode" automatically at 'Power ON'. In "Self-operation mode", AK2570 operates as below and keeps the emission intensity of the LD module constant by periodically applying the compensation voltage for the Biasand the Modulation- current against the temperature drift of the LD module.

In 50msec after the end of the resetting operation at 'Power ON', the data in EEPROM (Address = '1 1111 1111 [EINT memory]') is transferred to RINT and RATRM registers. Notice that the data in these registers can not change except the case of executing 'Power ON' again or re-writing the data with executing 'WRITE-REG' command in "Training mode'.

In "Self-operation mode", the T-SENSE converts the detected ambient temperature to the voltage. AD2 encodes this voltage to the 8bits digital data and transfers this data to RTMP register. This data is converted to the EEPROM address and utilized for reading the temperature characteristic data of the LD retained in the EEPROM. The EEPROM data is transferred to RDA1 ~ RDA3 registers and the output voltage of DA1 ~ DA3 are controlled. It is realized that the constant emission intensity of the LD is independent with the temperature drift by controlling the Bias- and the Modulation- current for the LD module and the alarm signal for the weakened LD. This behavior is executed periodically (the period is about 100ms). While operating in "Self-operation mode", it is impossible to execute any command except 'Command for Training mode'.



Note) REG0 register: This register synsthesizes the 32bits data and temporarily holds the data when transferring the data from the EEPROM to the registers.

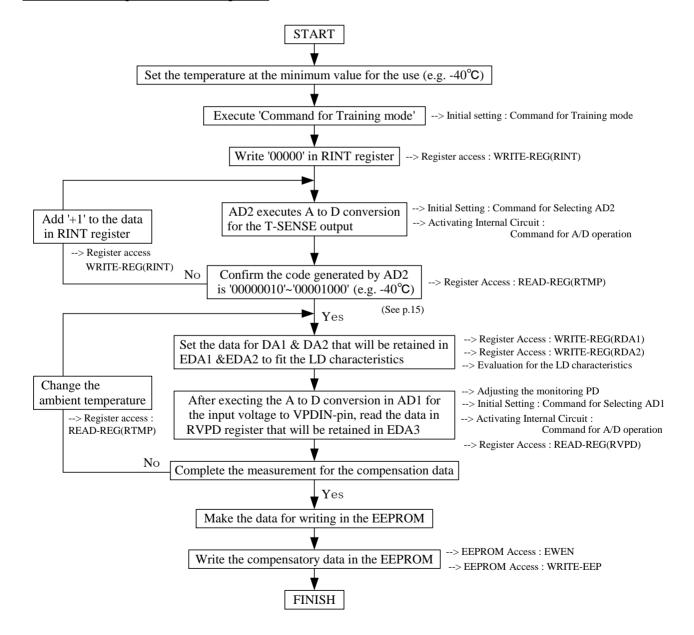
(2) Training mode

"Training mode" is used for the evaluation and the adjustment about AK2570. It is possible to write and read the data in the EERPOM and the registers and to execute activating the internal circuit for setting the temperature compensation data with the serial interface. Notice that it is possible to shift to "Training mode" by executing 'Command for Training mode' and any other command is not available while operating in "Self-operation mode".

After executing 'Command for Training mode', it is necessary to input the clock or the 'H' level signal to SK-pin continuously to keep the operational mode is in "Training mode". It is able to return to "Self-operational mode" by forcing the 'L' level signal to SK-pin for 50msec more in "Training mode".

In "Training mode", the periodical operation of temperature compensation for the LD is stopped. Also at the time of executing 'Command for Training mode' while operating in "Self-operational mode", AK2570 transfers to "Training mode" after completing the periodical operation.

www.DaRecommended sequence in "Training mode



I) Initial Setting

[1] Command for Self-operation mode

By executing 'Command for Self-operation mode', it is possible to transfer the mode from "Training mode" to "Self-operation mode".

[2] Command for Training mode

By executing 'Command for Training mode', it is possible to transfer the mode from "Self-operation mode" to "Training mode". Also any command except 'Command for Training mode' is not available while AK2570 operates in "Self-operation mode".

[3] Command for Selecting AD1

'Command for selecting AD1' is available in "Training mode". This command sets that AD1 (the A to D converter for the input voltage to VPDIN-pin) is enable for the operation and the selector between AD1 and www.DataShRVPD register is available. After this command is performed, the 8bits digital data of the VPDIN-pin signal encoded in AD1 is stored in RVPD register by executing 'Activating internal circuit - Command for A/D operation'.

[4] Command for Selecting AD2

'Command for selecting AD2' is available in "Training mode". This command sets that AD2 (the A to D converter for the output voltage from T-SENSE) is enable for the operation and the selector between AD2 and RTMP register is available. After this command is performed, the 8bits digital data of the T-SENSE output encoded in AD2 is stored in RTMP register by executing 'Activating internal circuit - Command for A/D operation'.

II) Activating internal circuit

[1] Command for A/D operation

'Command for A/D operation' makes that the selected A to D converter (AD1 or AD2) operates and the selected register (RVPD register or RTMP register) stores the data generated in the A to D converter selected by executing 'Command for Selecting AD1' or 'Command for Selecting AD2'. Also this command makes only that the selected register stores the 8bits digital data generated by the selected A to D converter.

[2] Command for Resetting data in RDA1-3

'Command for Resetting data in RDA1-3' sets that RDA1 ~ RDA3 registers hold the data retained in EEPROM which address is nominated by the data in RTMP register. Also this command is always available in "Training mode" and independent with the selector set by 'Command for Selecting AD1' or 'Command for Selecting AD2'.

III) Register Access

- [1] Command for reading the data in the register (READ-REG)

 It is able to read the data held in the nominated register by executing 'READ-REG' command.
- [2] Command for Writing the data in the register (WRITE-REG)

 It is able to write the data in the nominated register by executing 'WRITE-REG' command.

Register map

tegister ind	T															
Name	Address					Γ)ata						Function			
Name	Address	D23	~	D8	D7	D6	D5	D4	D3	D2	D1	D0	runction			
RTMP	000	X	?	X	D7	D6	D5	D4	D3	D2	D1	D0	Holding the data (temperature) generated by AD2			
RDA1	001	X	?	X	D7	D6	D5	D4	D3	D2	D1	D0	Holding the data for DA1			
RDA2	010	X	?	X	D7	D6	D5	D4	D3	D2	D1	D0	Holding the data for DA2			
RDA3	011	X	?	X	D7	D6	D5	D4	D3	D2	D1	D0	Holding the data for DA3			
RINT	100	X	?	X	X	X	X	D4	D3	D2	D1	D0	Holding the trimming data for T-SENSE [*1]			
RVPD	101	X	?	X	D7	D6	D5	D4	D3	D2	D1	D0	Holding the data (VPDIN) generated by AD1			
RATRM	110	X	~	X	X	X	X	D4	D3	D2	D1	D0	Holding the trimming data for ALMOUT [*2]			

^[*1] RINT register stores the initial data for the offset voltage of the T-SENSE

[*2] ATRM register stores the adjustment data for the alarm timing at the 50Mbps and the 156Mbps burst transmission (AKM recommends to use the EEPROM data for RATRM register already written at the shipment.)

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Initial register data

	l											
Name	Address	D23	~	D8	D7	D6	D5	D4	D3	D2	D1	D0
RTMP	000	X	~	X	1	1	1	1	1	1	1	1
RDA1	001	X	~	X	0	0	0	0	0	0	0	0
RDA2	010	X	~	X	0	0	0	0	0	0	0	0
RDA3	011	X	~	X	0	0	0	0	0	0	0	0
RINT	100	X	~	X	X	X	X	0	0	0	0	0
RVPD	101	X	~	X	0	0	0	0	0	0	0	0
RATRM	110	X	~	X	X	X	X	1	0	0	0	0

<Note> 'X' is indefinite, '1' or '0'.

IV) EEPROM Access

[1] Command for enabling to write the data in the EEPROM (EWEN)

'EWEN' command makes it possible to write the data in the EEPROM. It is necessary to execute this command before writing the data in the EEPROM, because it is automatically set at 'Power ON' to prohibit writing the data in the EEPROM. In "Training mode", it is always possible to write the data in the EEPROM after executing this command except the case of 'Power OFF' or executing 'EWDS' command.

[2] Command for prohibiting to write the data in the EEPROM (EWDS)

'EWDS' command makes it impossible to write the data in the EEPROM and it is the same setting at 'Power ON'. This command is available to change the setting to prohibit writing the data in the EEPROM without 'Power OFF'.

[3] Command for writing the data in the EEPROM (WRITE-EEP)

It is able to write the data in the nominated EEPROM by executing 'WRITE-EEP' command. And it is necessary to execute 'EWEN' command at first for permitting to write the data in the EEPROM.

[4] Command for reading the data in the EEPROM (READ-EEP)

It is able to read the data held in the nominated EEPROM by executing 'READ-EEP' command.

EEPROM map

Name	Addres	SS				Data	a													
Name	A8 - A	0	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0		
EDA12	0 0000	0000		The	data f	or RI	DA1 (8bit)			The data for RDA2 (8bit)									
EDA3	0 0000	0001		The	data f	or RI) DA3	8bit)				The	e unus	ed b	its (8	bit)				
EDA12	0 0000	0010		The	data f	or RI	DA1 (8bit)				The o	data fo	or RI	DA2	(8bit	t)			
EDA3	0 0000	0011		The data for RDA3 (8bit) The											unused bits (8bit)					
				I									I							
EDA12	1 1111	1100		The	data f	or RI)A1 (8bit)				The o	data fo	or RI	DA2	(8bit	t)			
EDA3	1 1111	1101		The data for RDA3 (8bit) The unused								ed b	its (8	bit)						
ERES	1 1111	1110		The reserved bits (16bit)																
EINT	1 1111	1111	The (3b	unuseo	l bits			for R		RM	The unused bits The data for (3bit) D4 - D0 (

Note> AKM cannot assure the period of the data retention (10years [min.] at 85°C) for 'The unused bits'.

2 Serial Interface

In "Training mode", it is able to execute the access to the EEPROM and the registers and to input the operational command for AK2570 with the 32bits serial data via 4pins consist of CS(#12), SK(#13), DI(#14) and DO(#15).

1) Constitution of the serial interface data

[a] "Initial setting", "Activating Internal Circuit" and "Register Access" (total 32bits)

Classification	Selection	Address	Data
4bits	1bit	3bits	24bits

[b] "EEPROM Access" (Total 32bits)

Classification	Command	Address	Data
4bits	2bits	10bits	16bits

<Note> These bits contain the arbitrary bit (the data is not definite, '0' or '1')'.

Please refer to the table in the next page.

<Note> Kindly pay attention when writing the data for RINT, because EINT also retains the data for RATRM register written at AKM.

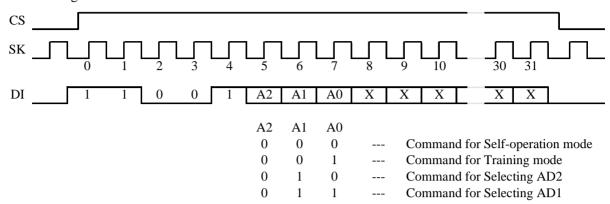
ii) Access to the serial interface

Classification	Select	Α	۸dd	ress												Dat	a												Execution
	1	0	C	0 0	х	X	x	X	x	X	X	х	X	X	X	X	X	X	x	x	x	X	X	X	Х	X	X	X	Command for Ordinary mode
1 1 0 0	1	0	C) 1	х	Х	Х	X	Х	Х	X	х	X	X	X	X	Х	X	X	Х	Х	X	Х	X	X	Х	Х	X	Command for Training mode
[1]Initial Setting	1	0	1	. 0	x	X	x	x	X	X	X	x	X	X	x	X	X	X	x	x	X	X	X	X	X	X	x	X	Command for Selecting AD2
	1	0	1	. 1	x	X	х	х	X	Х	X	х	X	Х	Х	Х	Х	Х	х	х	X	X	х	X	X	Х	х	Х	Command for Selecting AD1
1 1 1 1	1	0	C	0 0	х	X	x	X	X	x	X	х	X	X	X	X	X	X	x	x	x	X	X	X	Х	X	X	X	Command for A/D operation
[2]Activating Internal Circuit	1	0	C) 1	x	Х	х	Х	Х	Х	Х	х	X	Х	Х	Х	Х	X	х	Х	Х	Х	Х	X	Х	Х	х	Х	Command for Resetting data in RDA1-3
	0	0	c	0 0	х	X	x	X	x	x	X	x	X	X	X	X	X	X	x	x	D7	D6	D5	D4	D3	D2	D1	D0	READ-REG (RTMP)
	0	0	C) 1	х	X	Х	X	X	Х	X	х	X	X	X	X	X	X	X	X	D7	D6	D5	D4	D3	D2	D1	D0	READ-REG (RDA1)
	0	0	1	. 0	x	X	x	X	X	X	X	х	X	X	X	X	X	X	x	X	D7	D6	D5	D4	D3	D2	DI	D0	READ-REG (RDA2)
	0	0	1	. 1	х	X	Х	Х	X	X	X	х	X	X	X	X	X	X	Х	X	D7	D6	D5	D4	D3	D2	D1	D0	READ-REG (RDA3)
eel4U.com	0	1	c	0 0	x	X	x	x	x	x	X	x	X	X	X	X	X	X	x	x	x	X	x	D4	D3	D2	Di	D0	READ-REG (RINT)
	0	1	C) 1	x	X	Х	X	X	X	X	х	X	X	X	X	X	X	X	X	D7	D6	D5	D4	D3	D2	DI	D0	READ-REG (RVPD)
1 1 1 0	0	1	1	. 0	x	X	x	X	X	X	X	х	X	Х	X	X	X	X	x	X	X	X	X	D4	D3	D2	DI	D0	READ-REG (RATRM)
[3]Register Access	1	0	C	0 (x	X	Х	Х	X	Х	X	х	X	X	X	X	X	X	Х	X	D7	D6	D5	D4	D3	D2	D1	D0	WRITE-REG (RTMP)
	1	0	c) 1	x	X	x	x	X	x	X	x	X	X	X	X	X	X	x	X	D7	D6	D5	D4	D3	D2	DI	D0	WRITE-REG (RDA1)
	1	0	1	. 0	x	X	X	X	X	Х	X	х	X	X	X	X	X	X	X	X	D7	D6	D5	D4	D3	D2	D1	D0	WRITE-REG (RDA2)
	1	0	1	. 1	х	X	x	X	x	x	X	x	X	X	X	X	X	X	x	x	D7	D6	D5	D4	D3	D2	DI	D0	WRITE-REG (RDA3)
	1	1	C	0 (x	X	Х	Х	X	Х	X	х	X	X	X	X	X	X	Х	X	X	Х	х	D4	D3	D2	D1	D0	WRITE-REG (RINT)
	1	1	c) 1	x	X	x	x	x	x	X	x	X	X	X	X	X	X	x	x	D7	D6	D5	D4	D3	D2	DI	D0	WRITE-REG (RVPD)
	1	1	1	. 0	x	Х	х	х	Х	х	Х	х	X	X	Х	Х	Х	X	Х	х	Х	X	х	D4	D3	D2	DI	D0	WRITE-REG (RATRM)
	0	0	C	0 0	0	X	x	X	x	x	X	x	X	X	X	X	X	X	x	x	x	X	x	X	X	x	x	X	EWDS
1 1 0 1	0	0	1	1	1	Х	Х	Х	Х	Х	Х	х	X	X	X	X	X	X	X	Х	X	Х	Х	X	Х	Х	X	X	EWEN
[4]EEPROM Access	0	1	х	A	A7	A	A_5	A4	A3	A2	A1	A0	D15	D14	D13	D12	D11	D10	D9	$ _{D8}$	D7	D6	D5	D4	D3	D2	D1	D0	WRITE-EEP
	1	0	Х	A	3 A7	Αć	A5	A4	А3	A2	A2 A1 A0 D15 D14 D13 D12 D11 D10 D9 D8 D7 D6 D5 D4 D3 D2 D1 D0							D0	READ-EEP										
Classification	Comma	and					Ado	lress	S										Da	ata									Execution

Note) 'x' in this table is not definite, '0' or '1'.

III) Timing for the serial interface

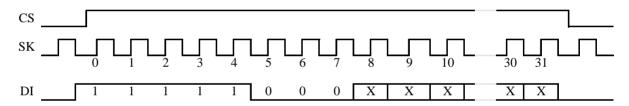
[1] Initial Setting



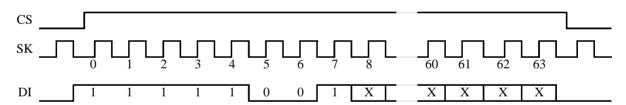
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[2] Activating Internal Circuit

[a] Command for A/D operation



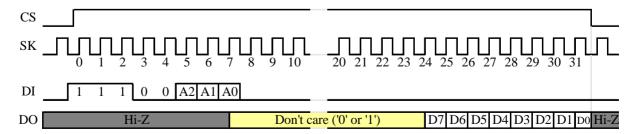
[b] Command for Resetting data in RDA1-3



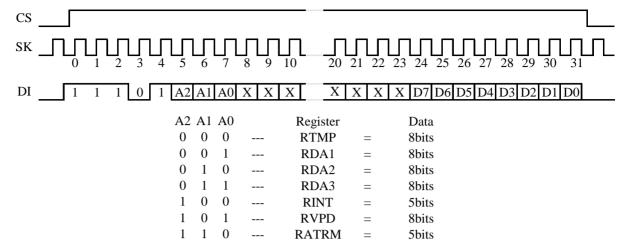
<Note> In the case of executing 'Command for Resetting data in RDA1-3', it is necessary to input the 64 clocks to SK-pin with keeping to force the 'H' level signal to CS-pin.

[3] Register Access

[a] Command for reading the data in register(READ-REG)



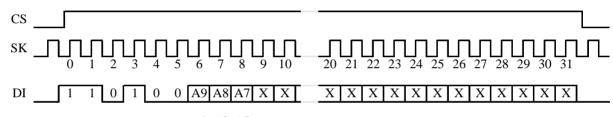
[b] Command for writing the data in the register (WRITE-REG)



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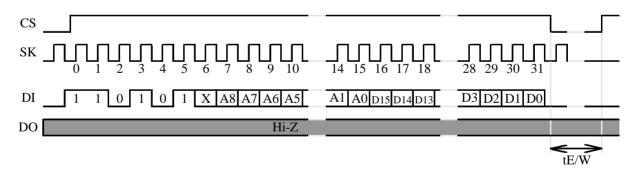
[4] EEPROM Access

[a] Command for enabling/prohibiting to write the data in the EEPROM (EWEN/EWDS)

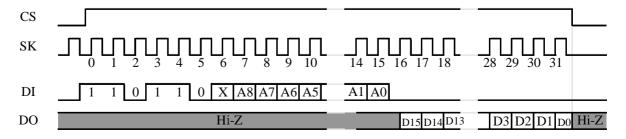


A9 A8 A7 0 0 0 --- EWDS command 1 1 1 --- EWEN command

[b] Command for writing the data in the EEPROM (WRITE-EEP)

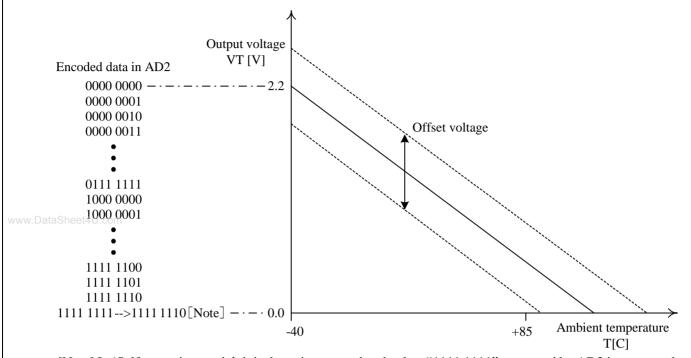


[c] Command for reading the data in the EEPROM (READ-EEP)



3. Thermo-sensor (T-SENSE)

Kindly see the figure below that shows the relationship between the detected ambient temperature (T) and the generated output voltage (VT) in the T-SENSE.



[Note] In 'Self-operation mode', it is the unique case that the data "1111 1111" generated by AD2 is converted to "1111 11110" automatically and the EEPROM data in the address '1 1111 110X' is used as the compensation data, this is the reason why that the EEPROM which address is "1 1111 111X" retains the reserved data and the trimming data for the T-SENSE and the ALMOUT.

VT is 2.2V (Typ.) at -40°C and 0.0V at 85°C above and has the distribution due to each LSI. However it is possible to cancel the distributed offset voltage arising in the T-SENSE among LSIs by setting the data (D4 ~D0) in RINT register. The offset cancel voltage (Reference) corresponding to the data (D4 ~D0) in RINT register is shown in the table below.

RINT register	Offset cancel voltage [mV]
D4 D3 D2 D1 D0	(Reference)
1 1 1 1 1	+375
1 1 1 1 0	+350
1 1 1 0 1	+325
1 1 1 0 0	+300
1 0 0 0 1	+25
1 0 0 0 0	0
0 1 1 1 1	-25
0 0 0 1 1	-325
0 0 0 1 0	-350
0 0 0 0 1	-375
0 0 0 0 0	-400

*Set up for the RINT register

The offset voltage arising in the T-SENSE is slightly different and has the distribution among the LSIs. Please adjust that the data in RTMP register exists between the 'Minimum code' and the 'Maximum code' shown in this table at the 'Minimum ambient temperature for the use' with writing the data in RINT register in "Training mode", and refer to 'Recommended sequence in "Training mode" in p.7.

Minimum ambient temperature for the use	Minimum code	Maximum code
0°C	01000010	01001000
-20°C	00100010	00101000
-30°C	00010010	00011000
-40°C	00000010	00001000
In the case of fitting at +25°C(Reference)	01100110	01101100

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1LSB of AD2 output data (8bits) is 8.63mV (Typ.). Therefore 6codes is 51.8mV (Typ.) corresponding to the range between 'Minimum code' and 'Maximum code' shown in above table. On the other hand, the step of the offset cancel voltage is 25mV (Typ.) and it is possible to adjust the output voltage of the T-SNESE in the range of 'Minimum code' and 'Maximum code'.

After this offset voltage adjustment, the output voltage from the T-SENSE becomes appropriate for the AD2 input range at every ambient temperature (-40° C $\sim +85^{\circ}$ C). Also the 'Minimum code' and the 'Maximum code' for this adjustment increase 16 codes/10°C.

4. D to A converter (DA1 and DA2)

In the normal operation, forcing the 'L' level signal to SHUTDN-pin makes that DAOUT1 (the output of DA1 +AMP1) and DAOUT2 (the output of DA2+AMP2) utput the voltage corresponding to the data in RDA1 and RDA2 registers.

On the other hand, forcing the 'H' level signal to SHUTDN-pin makes that DAOUT1 and DAOUT2 output 0V (Min.). Also the data in RDA1 and RDA2 registers does not change and is held while forcing 'Shut down signal (the 'H' level)'. By forcing the 'L' level signal to SHUTDN-pin again, DAOUT1 and DAOUT2 output the signal corresponding the continuously held data in RDA1 and RDA2 registers.

5. Alarm circuit (DA3, ALMOUT, Comparator and ALM Timing Generator)

I) Mode setting

The alarm circuit has the 3 modes (the Continuous mode, the 156Mbps burst transmission mode and the 50Mbps burst transmission mode). Each mode is set by the signals forced to ALMMOD0-pin and ALMMOD1-pin.

ALMMOD1	ALMMOD0	Mode
0	0	the Continuous mode
0	1	the 50Mbps burst transmission mode
1	0	the 156Mbps burst transmission mode
1	1	Prohibited

II) Continuous mode

The alarm circuit compares the input voltage to VPDIN-pin (the monitoring PD signal) and the output voltage from DA3 (the alarm threshold level). The data for the alarm threshold level is retained in the EEPROM (EDA3), transferred to RDA3 and converted D to A signal in DA3. At any time, the 'H' level alarm signal can be generated and outputted from ALM-pin in the case that the input voltage to VPDIN-pin becomes lower than the output voltage of DA3.

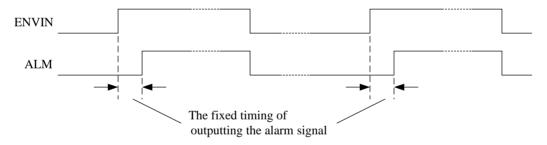
III) 50Mbps burst transmission mode and 156Mbps burst transmission mode

The alarm circuit compares the input voltage to VPDIN-pin (the monitoring PD signal) and the output voltage from DA3 (the alarm threshold level). The data for the alarm threshold level is retained in the EEPROM (EDA3), transferred to RDA3 and converted D to A signal in DA3.

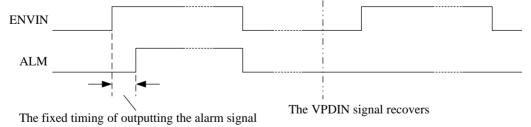
The alarm circuit detects the polarity of the input signal to ENVIN-pin at the constant timing (the detecting eet4U.com point) from the rising edge ('L'à 'H') of this signal. The alarm circuit outputs the alarm signal (the 'H' level) from ALM-pin in the case that the input voltage to VPDIN-pin is lower than the output voltage from DA3 and ENVIN signal is still kept at the 'H' level. Also the alarm circuit detects the rising edge of the ENVIN signal and fixes the constant timing to output the alarm signal.

In the case that VPDIN signal recovers and becomes higher than the alarm threshold level at the detecting point with ENVIN = 'H' or that the ENVIN signal becomes the 'L' level, the alarm circuit outputs the 'L' level (the normal signal) from ALM-pin.

* In the case of outputting the alarm signal continuously



* In the case of stopping the alarm signal (the VPDIN signal recovers)



ABSOLUTE MAXIMUM RATING

Parameter	Symbol	Min.	Max.	Unit	Remark
Power supply voltage	VDD	-0.3	6.0	V	DVDD-pin, AVDD-pin
Ground level	VSS	0.0	0.0	V	DVSS-pin, AVSS-pin
Digital input voltage	VDIN	-0.3	VDD+0.3	V	
Analog input voltage	VAIN	-0.3	VDD+0.3	V	
Input current	IIN	-10	10	mA	Except the pins above
Storage temperature	TSTG	-55	+125	°C	

<Note> AK2570 may operate abnormally and be broken under the condition exceeding the range shown above.

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RECOMMENDED OPERATING CONDITION

AKM can assure the characteristics of AK2570 specified in this data sheet under the condition as below.

Parameter	Symbol	Min.	Тур.	Max.	Unit	Remark
	VDD	2.97	3.30	3.63	V	
Power supply voltage	VSS	0.0	0.0	0.0	V	
Ambient temperature for operation	Та	-40		85	°C	

ELECTRICAL CHARACTERISTICS

(1) Power Consumption

Parameter	Symbol	Min.	Тур.	Max.	Unit	Remark
Consumptive current	IDD			30	mA	

<Note> The consumptive current which does not include the driving current for the outputs is measured under the condition that the digital input pins are connected to VSS or VDD.

(2) EEPROM characteristics

	Parameter	Min.	Тур.	Max.	Unit	Remark
	EEPROM total writing times	10000			time	
	EEPROM data retention 1	10			year	85°C
www.DataS	neet4EEPROM data retention 2	300			year	50°C (Reference)

(3) Digital Part

[a] DC characteristics

Parameter	Symbol	Condition	Min.	Тур.	Max.	Unit
Input higher voltage	VIH		0.7VDD		VDD	V
Input lower voltage	VIL		VSS		0.3VDD	V
Input higher current	IIH	VIH = VDD			10	μΑ
Input lower current	IIL	VIL = 0V	-10			μΑ
Output higher voltage	VOH	IOH = -0.2mA	0.9VDD			V
Output lower voltage	VOL	IOL = 0.2mA			0.1VDD	V

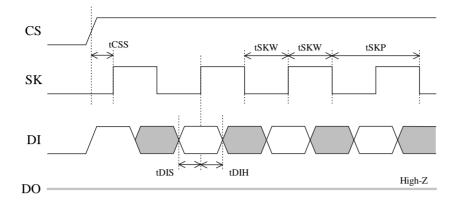
[b] AC characteristics

7 C Characteristics	l	I				
Parameter	Symbol	Condition	Min.	Тур.	Max.	Unit
GK D : 1	tSKP	While A/D conversion	10			μs
SK : Period	tSKP	While other operation	2			μs
SK : Pulse duty	tSKW		40		60	%
Delay time : CS='H' to SK='H'[*]	tCSS		150			ns
Delay time : SK='L' to CS='L'	tCSH		0			ns
Time for setting up the data	tDIS		200			ns
Time for holding the data	tDIH		200			ns
Delay time for the output	tPD	CL = 100pF			1	μs
Time to write in the EEPROM	tE/W		10			ms
CS : Minimum time in the 'L' level	tCS		250			ns
Delay time : CS='L' to DO='Hi-Z'	tOZ				100	ns

^[*] It is necessary to force the 'L' level to SK-pin at the rising edge of the CS signal and to apply the clock to SK-pin at 150msec or more after this rising edge of the CS signal.

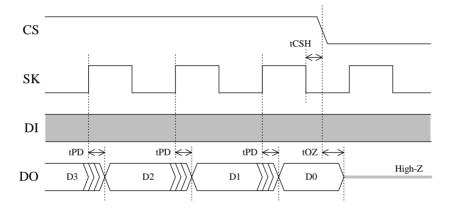
<u>Digital Part – AC characteristics : Timing</u>

[1] Timing for the command input

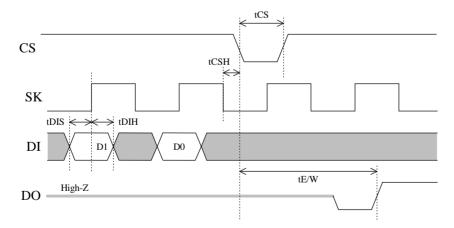


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[2] Timing for the data output



[3] Timing for writing the data in the EEPROM



(4) Analog part

[a] Input characteristics of the A to D converter

<1> AD1

17 1101									
Resolution		8bits linear							
Conversion time		About 150µs or 15 SK clocks							
DNL		± 2LSB							
Input range 1 (Peak voltage)	$0.0V \sim 1.0V [Typ]$								
	MSB							LSB	Input voltage
	D7	D6	D5	D4	D3	D2	D1	D0	
	1	1	1	1	1	1	1	1	à 1.0V
	1	1	1	1	1		1	0	
et4U.com	(Straight binary)								
	0	0	0	0	0	0	0	1	
	0	0	0	0	0	0	0	0	à 0.0V

<2> AD2

\ <u>\\ \Z \range \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \</u>										
Resolution		8bits linear								
Conversion time		About 150µs or 15 SK clocks								
DNL		± 0.7LSB								
Input range 2 (Temperature)		0.0V ~ 2.2V [Typ.]								
	MSB							LSB	Input voltage	
	D7	D6	D5	D4	D3	D2	D1	D0	(Detected temperature)	
	0	0	0	0	0	0	0	0	à 2.2V (-40°C)	
	0	0	0	0	0	0	0	1		
			(Str	aight	bina	ry)				
	1	1	1	1	1	1	0	1		
	1	1	1	1	1	1	1	0	à 0.0V (>85°C)	

[b] Output characteristics of the A to D converter

<1> DA1, DA2

Parameter	Min.	Тур.	Max.	Unit	Remark
Resolution		8		bit	Circuit design
DNL	-1/2		+1/2	LSB	
Maximum output voltage	0.425	0.500	0.575	V	±15% <note></note>
Minimum output voltage	0.0		10.0	mV	
Output voltage at the shut down operation	0.000		5.000	mV	SHUTDN-pin is forced 'H'
Output current	2.50			mA	Input code =181 (dec)

<Note $> \pm 5\%$ included in the range $\pm 15\%$ is the distribution caused by the fluctuations of the power source voltage and the ambient temperature.

<2> The over shoot voltage of DA1 and DA2 at relieving the shut down operation

Input data for DA1 and DA2	Min.	Тур.	Max.	Unit	Remark	
11111111						
11111110					Designation	
1			'Output voltage'×1.2	mV	Designed guarantee value	
00001001					value	
00001000						
00000111						
00000110			12.0		Designed guarantes	
			13.0 (Stabilized in 120µs)	mV	Designed guarantee value	
00000001			(Stabilized III 120µs)		value	
0000000						

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<3> DA3

	Min.	Тур.	Max.	Unit	Remark
Resolution		8		bit	Circuit design
Voltage step by 1 code		3.92		mV	Designed guarantee value
Maximum output voltage		1.00		V	Designed guarantee value
Minimum output voltage		0.00		mV	Designed guarantee value

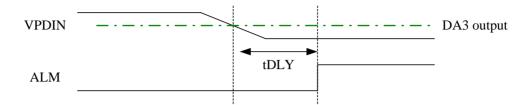
<4> Relationship between the input digital code and the output voltage

D to A converter	Digital code	Output voltage (Typ.)		
	11111111	500mV		
DA1				
2111	00000001	1.96mV		
	00000000	0.0V		
	11111111	500mV		
DA2				
	00000001	1.96mV		
	00000000	0.0V		
	11111111	1.0V		
DA3				
	00000001	3.92mV		
	00000000	0.0V		

[c] Output characteristics of the alarm signal

<1> Continuous mode

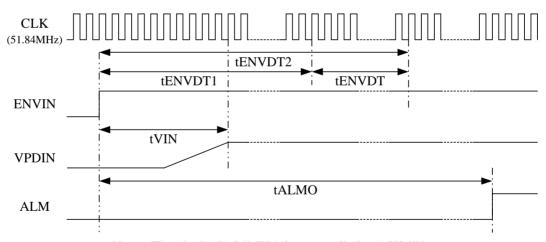
Parameter	Symbol	Condition	Min.	Тур.	Max.	units
D. CAIM : 1 DIV	DA3 output=0.5V			100		
Delay time of ALM signal	tDLY	VPDIN=2.0V à 0V			100	ns



<2> 50Mbps burst transmission mode

25 5 01/10 ps outst transmission mode						
Parameter Parameter	Symbol	Condition	Min.	Тур.	Max.	unit
Start time for detecting ENV signal	tENVDT1		463.0			ns
Total time for detecting ENV signal	tENVDT2				617.3	ns
Time for detecting ENV signal	tENVDT				154.3	ns
Time for confirming VPDIN signal	tVIN			212.2		ns
Time for outputting ALM signal	tALMO	CL=20pF	463.0		771.6	ns

^[*] The condition of measuring for the 'Time for outputting ALM signal' is that the input voltage to VPDIN-pin is 0.0V (constant).



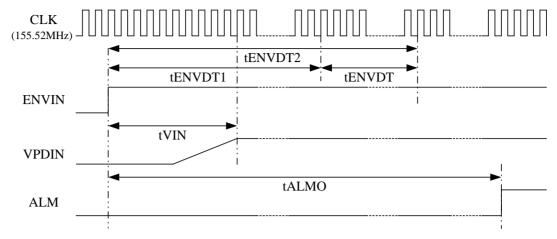
<Note> The clock (51.84MHz) is not applied to AK2570.

<3> 156Mbps burst transmission mode

Parameter	Symbol	Condition	Min.	Тур.	Max.	unit
Start time for detecting ENV signal	tENVDT1		167.2			ns
Total time for detecting ENV signal	tENVDT2				218.8	ns
Time for detecting ENV signal	tENVDT				51.4	ns
Time for confirming VPDIN signal	tVIN			64.3		ns
Time for outputting ALM signal	tALMO	CL=20pF	167.2		372.9	ns

^[*] The condition of measuring for the 'Time for outputting ALM signal' is that the input voltage to

VPDIN-pin is 0.0V (constant).



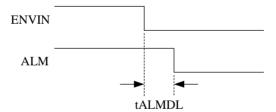
<Note> The clock (155.52MHz) is not applied to AK2570.

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Delay time between the falling edge of ENVIN and that of ALM

In the 50Mbps burst transmission mode and the 156Mbps burst transmission mode, the ALM signal becomes the 'L' level in the case of that the ALM signal is still generated (at the 'H' level) and the 'L' level signal is forced to ENVIN-pin (ENV signal). There is the delay time between the falling edge of the ENV signal and that of the ALM signal in this case.

Parameter	Symbol	Condition	Min.	Тур.	Max.	unit
Delay time between the falling edge of ENVIN and that of ALM	tALMDL	CL=20pF			19.3	ns



Error on the judgment for ALM signal

There is some error on the judgment for generating the alarm signal. Therefore ALM signal will be often generated in the case that the input voltage to VPDIN-pin is slightly bigger than the DA3 output (the alarm threshold level). The error shown below is the value against the DA3 output.

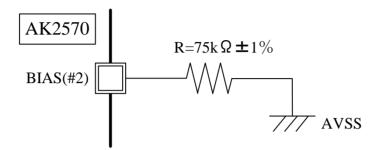
DA3 output (Typ.)	Error on the judgment for ALM signal [*]	Remarks
58.8mV	± 3dB	Designed reference value
98.0mV	± 2dB	Designed reference value

[*] dB = the converted value for the power

RECOMMENDED EXTERNAL CIRCUIT

[1] BIAS-pin for the reference voltage

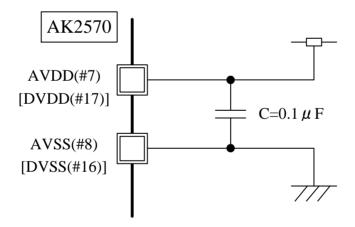
Kindly connect the resistance (the $\pm 1\%$ accuracy) between BIAS-pin and AVSS with the line pattern as short as possible.



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[2] Power pins

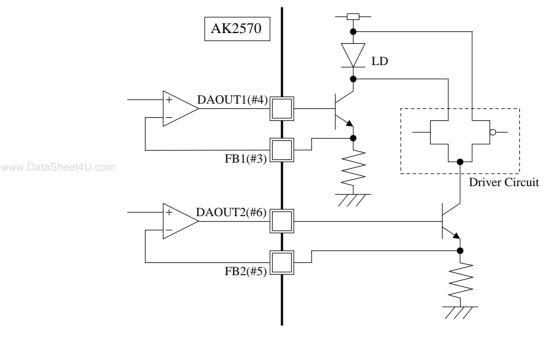
Kindly insert the capacitor as shown below between DVDD-DVSS and AVDD-AVSS.



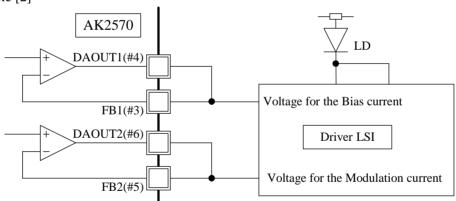
EXAMPLE for EXTERNAL CIRCUIT

[a] The examples of the external circuit for DAOUT1-pin / FB1-pin and DAOUT2-pin / FB2-pin are shown below in the case of the use at the direct variation for the LD.

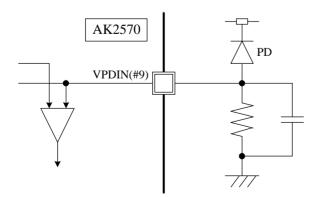
<1> Example [1]



<2> Example [2]



[b] The example of the external circuit for VPDIN-pin is shown below.



PACKAGE

Package type: 20pin - SSOP

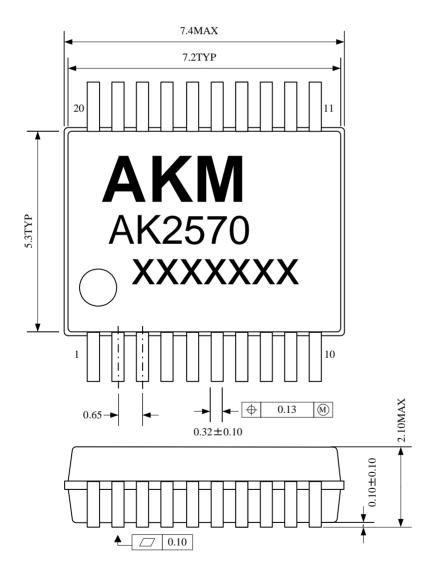
Marking on the surface of the package:

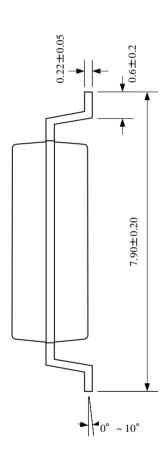
(1) Index : Indicating Pin #1(2) Company name : AKM(3) Product No. : AK2570

(4) Date code: XXXXXXX (7 figures)

Package size:

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 - (b) A critical component is one whose failure to function or perform may reasonably be expected to result, whether directly or indirectly, in the loss of the safety or effectiveness of the device or system containing it, and which must therefore meet very high standards of performance and reliability.
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